



Agilent Technologies

TDR and VNA: The Right Tools for the Right Measurements

August 20, 2002

presented by:

Eric Bogatin, GigaTest Labs

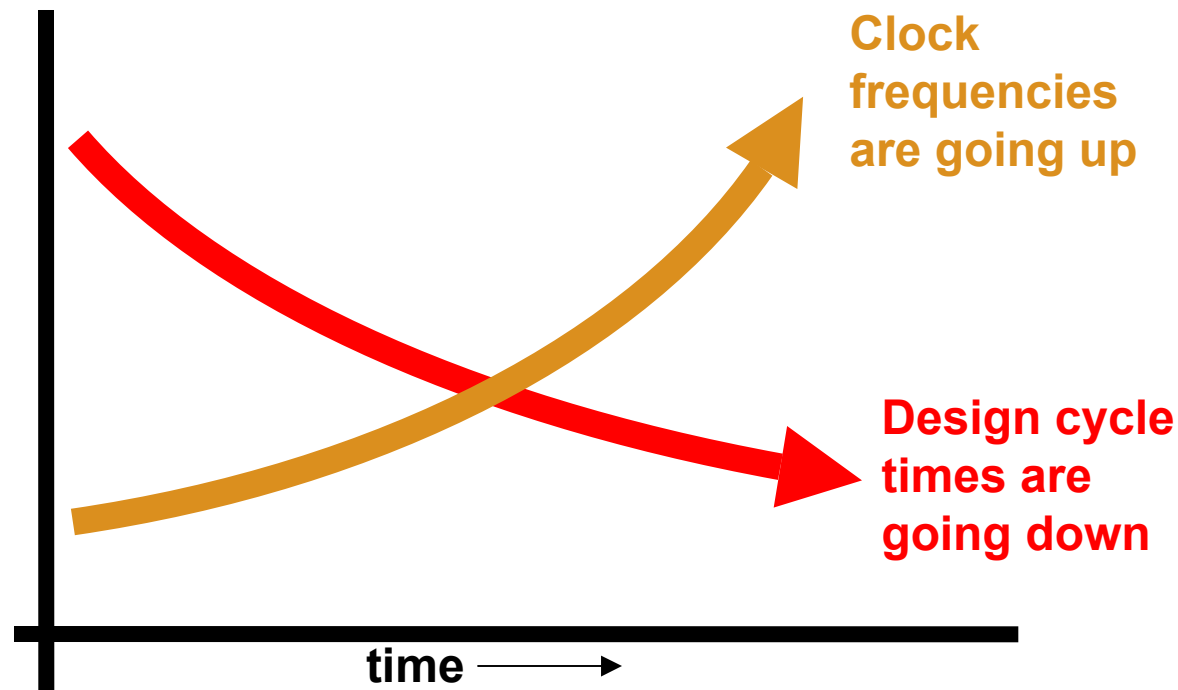
Jeff Tehan, Agilent

Mike Resso, Agilent

Overview

- **Why characterization will be in your future**
- **TDR (Time Domain Reflectometer) and VNA (Vector Network Analyzer) systems: similarities and differences**
- **TDR techniques**
- **VNA techniques**
- **The right tool for your applications**

High Speed Product Design will only get Harder



- Key ingredient to the new high speed design methodology: *predictability*
- Measurements are essential to reduce *risk*

The Critically Important Role of Measurements

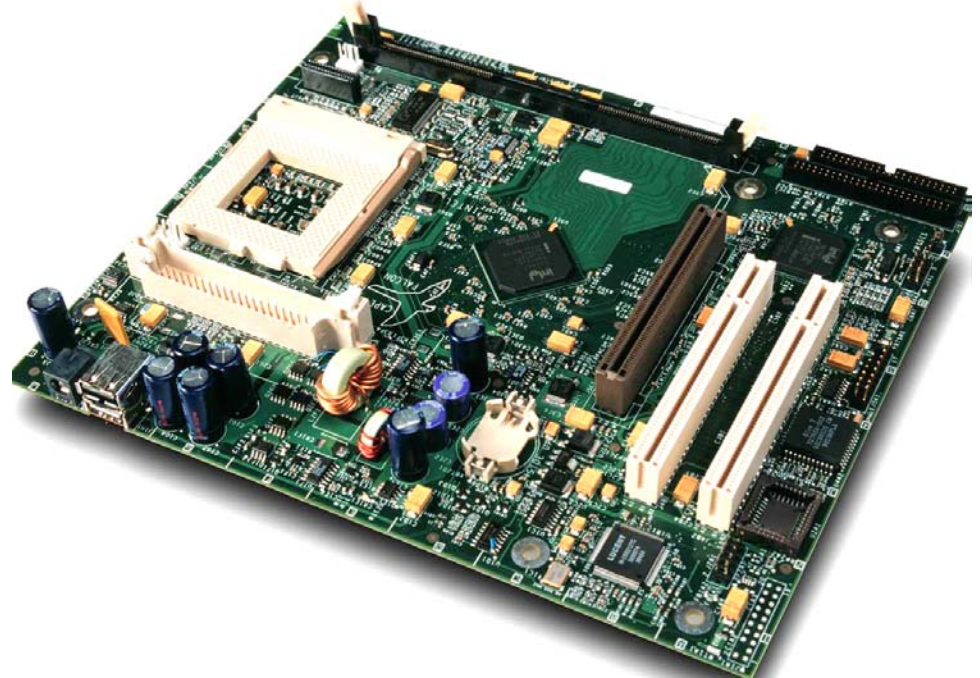
Create a model from a real structure

Validate a model and simulation from a calculation (anchor to reality)

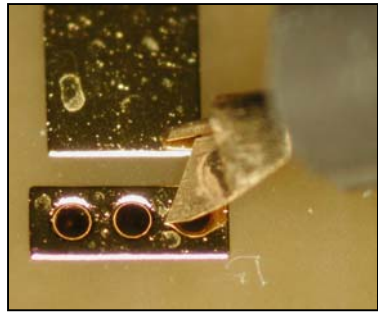
Emulate the system level performance

VNA and TDR Based Measurements

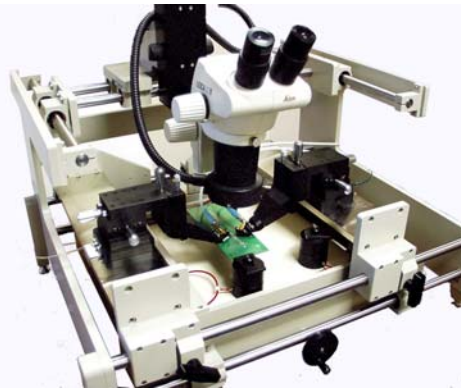
- When an external precision signal is required
- Applies to any passive interconnect or component
 - Discretes
 - Packages
 - Connectors
 - PCB structures
 - Material properties



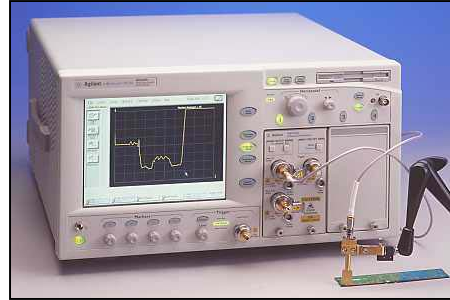
Complete Characterization System Solutions



DUT +
microprobes

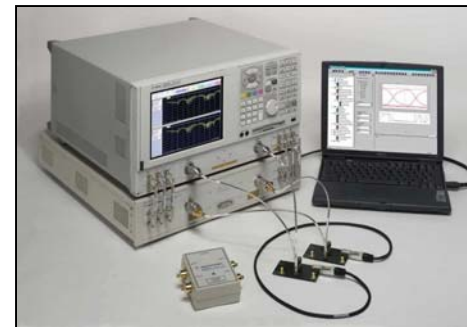
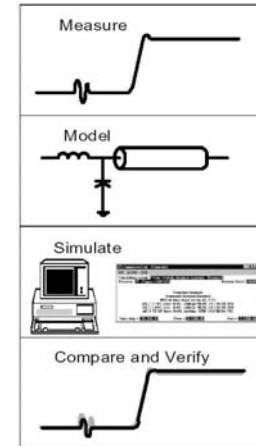


GigaTest Probe
Station



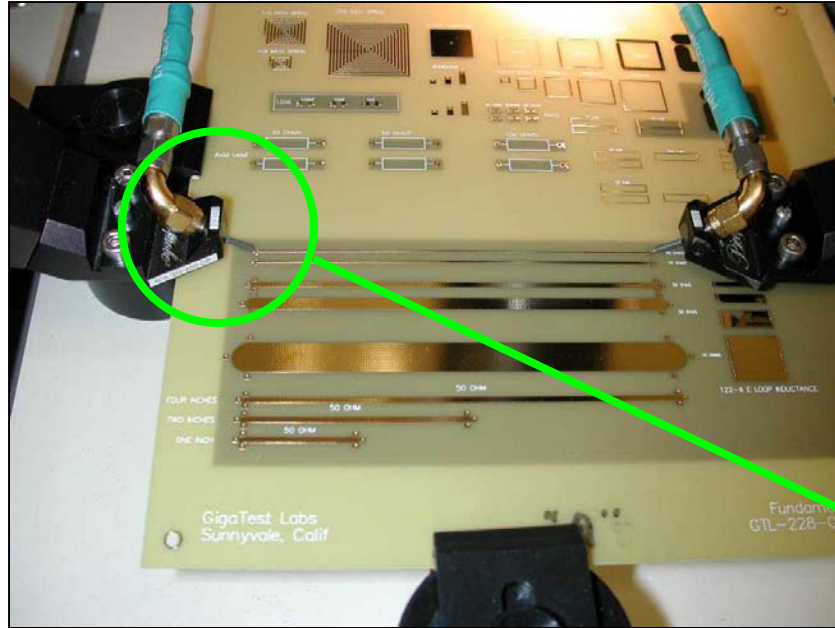
TDR

TDA Systems IConnect

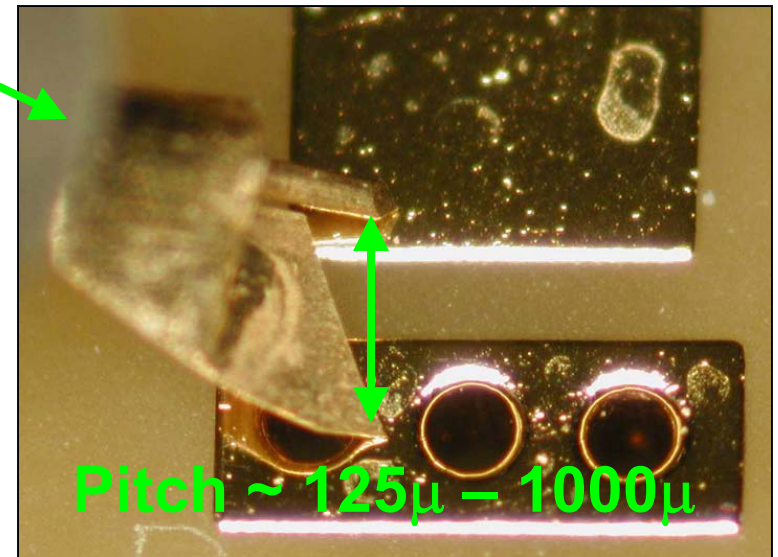


Physical Layer Test System
(PLTS): VNA + software

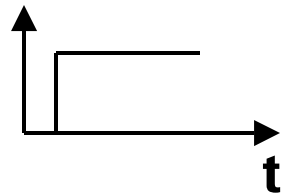
Microprobes Allow Precision Probing of Structures with Minimal Artifacts



Close up



TDR and VNA Techniques



Incident wave

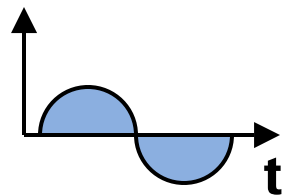
Reflected wave

TDR

DUT

Transmitted wave

TDT



Incident wave

Reflected wave

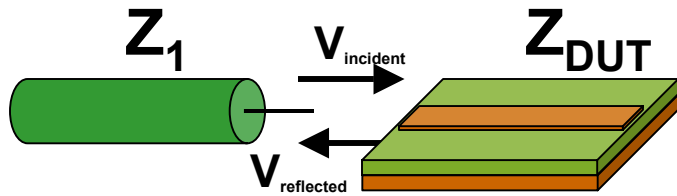
S11

DUT

Transmitted wave

S21

Impedance in the Time or Frequency Domains



$$\frac{V_{reflected}}{V_{incident}} = \frac{Z_{DUT} - Z_1}{Z_{DUT} + Z_1}$$

Time domain

$$\rho = \frac{V_{reflected}}{V_{incident}}$$

$$Z_{DUT} = 50\Omega \frac{1 + \rho}{1 - \rho}$$

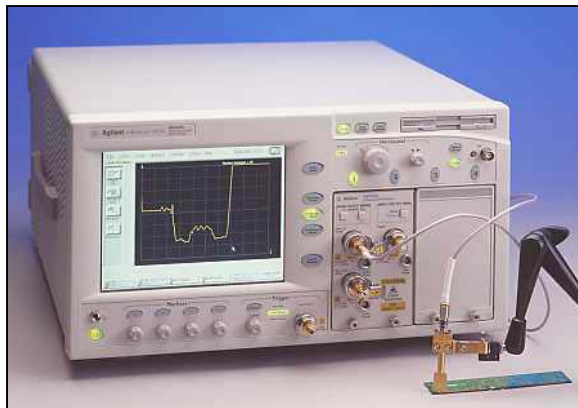
Frequency domain

$$S_{11} = \frac{V_{reflected}}{V_{incident}}$$

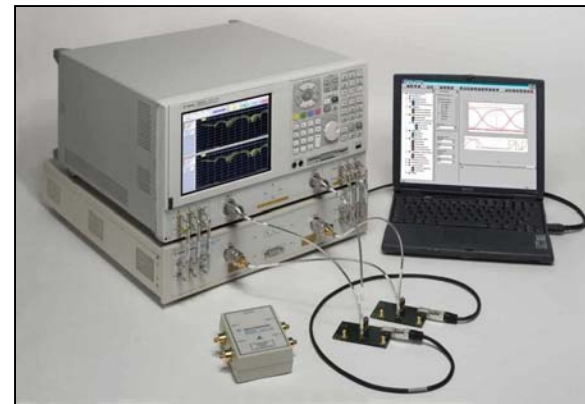
$$Z_{DUT} = 50\Omega \frac{1 + S_{11}}{1 - S_{11}}$$

There is no fundamental difference in the information content between the time domain and the frequency domain

There is a difference in the capabilities of the two systems:



TDR + TDA Systems IConnect



Agilent PLTS

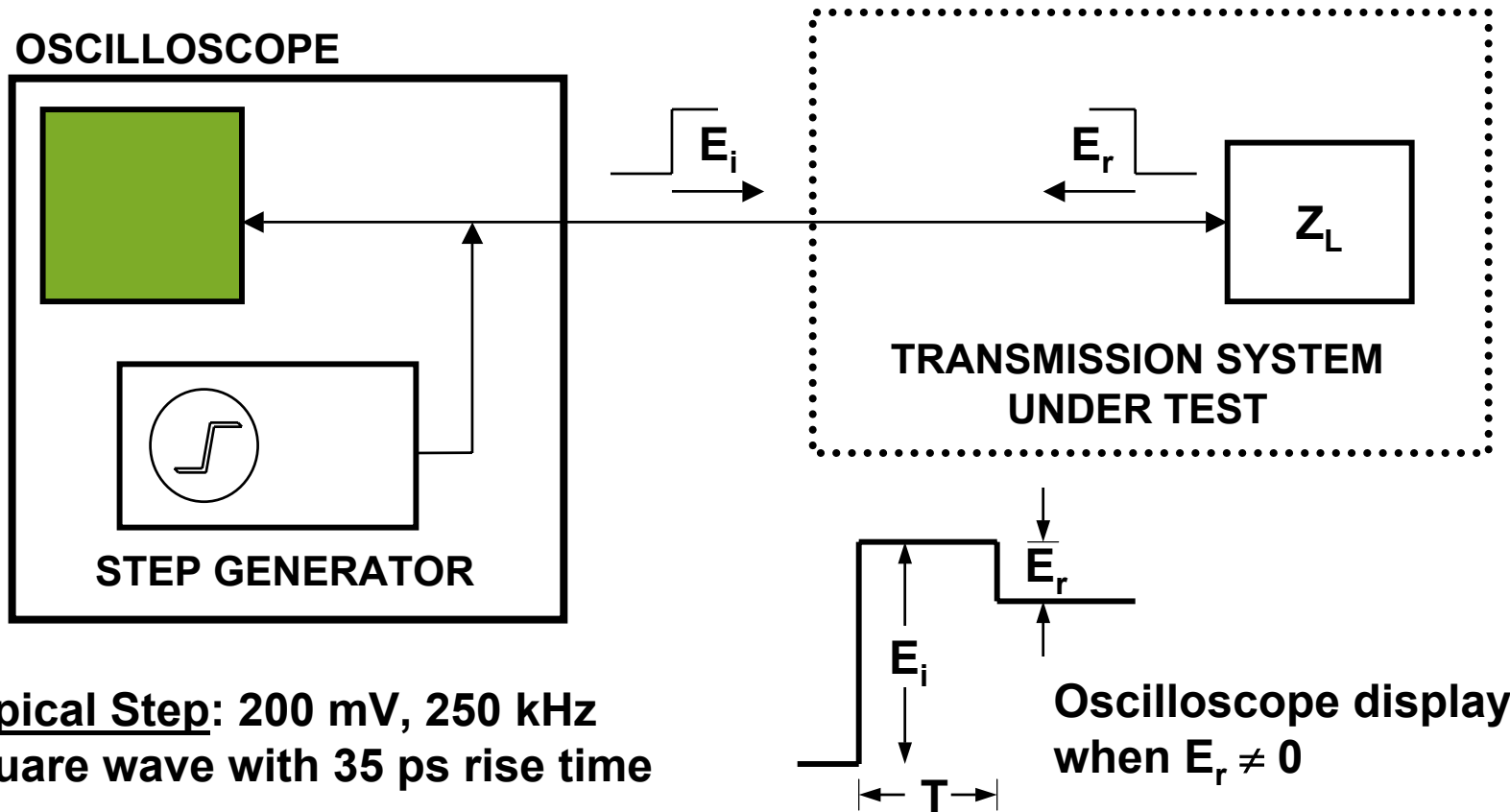
TDR and VNA Systems: What's the Difference?

- **Great deal of overlap in features, capabilities: T lines, discontinuities, cross talk, differential impedance, ...**
- **A TDR is simple to use and can be quickly set up for general applications: transmission lines and discontinuities**
- **SNR is better for VNA than TDR**
 - **important for low insertion loss components**
 - **Important for low levels of mode conversion**
- **The PLTS simplifies the analysis of 4 port differential interconnects**

TDR Agenda

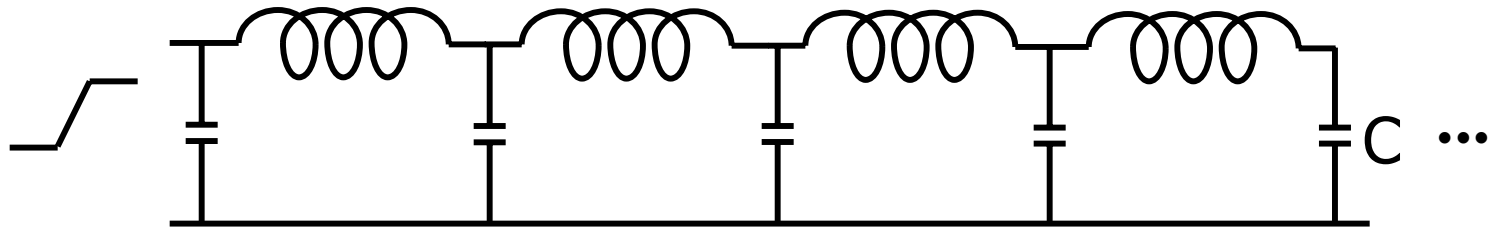
- **TDR Overview - What is it?**
- **Impedance Problems - Where are they?**
- **Microstrip Examples**
- **Excess Reactance**
- **TDR vs. TDT**
- **TDR Normalization**
- **Real World TDR Set up**

What is TDR? (Time Domain Reflectometry)



Typical Step: 200 mV, 250 kHz
square wave with 35 ps rise time

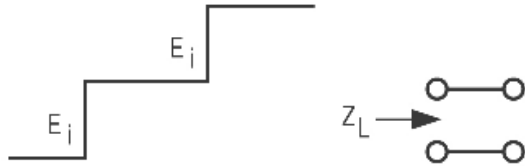
Transmission Line Model



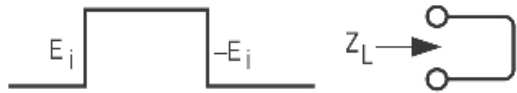
$$Z_0 = \sqrt{L/C}$$

Discontinuities occur when the impedance changes. This will happen when the L or C changes or an R is introduced.

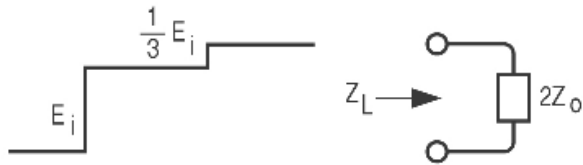
Basic TDR Waveform Analysis



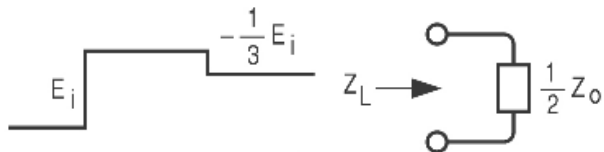
(A) Open Circuit Termination ($Z_L = \infty$)



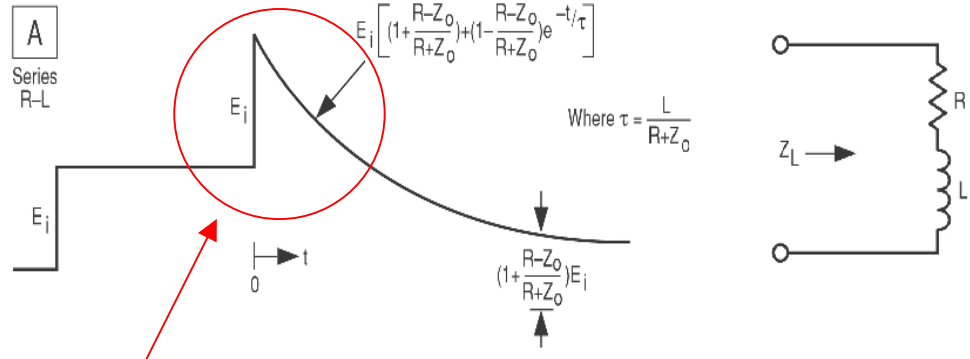
(B) Short Circuit Termination ($Z_L = 0$)



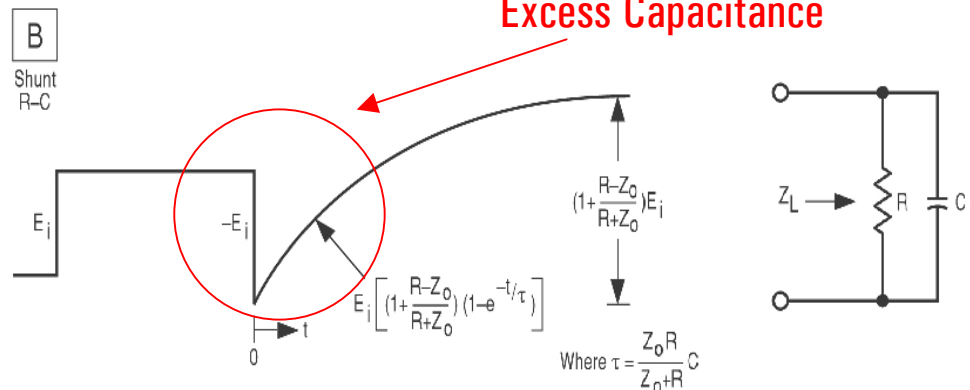
(C) Line Terminated in $Z_L = 2Z_0$



(D) Line Terminated in $Z_L = \frac{1}{2}Z_0$

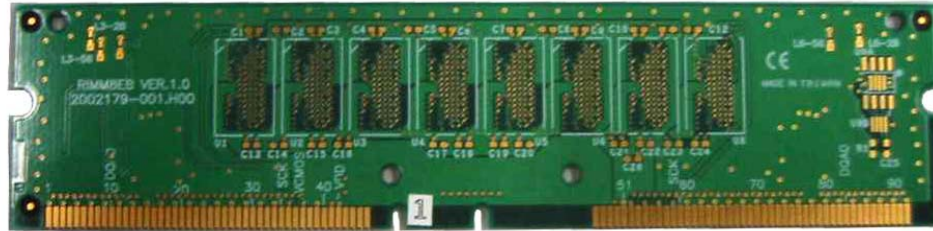


Excess Inductance



Excess Capacitance

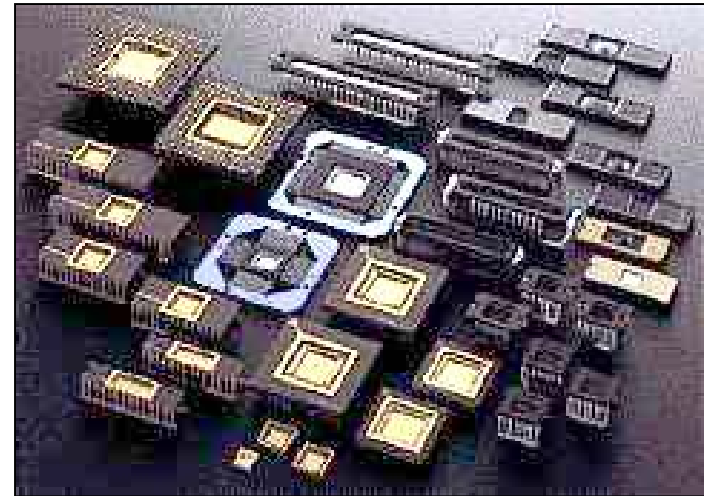
Impedance Problems are Everywhere



PC BOARDS BACKPLANES

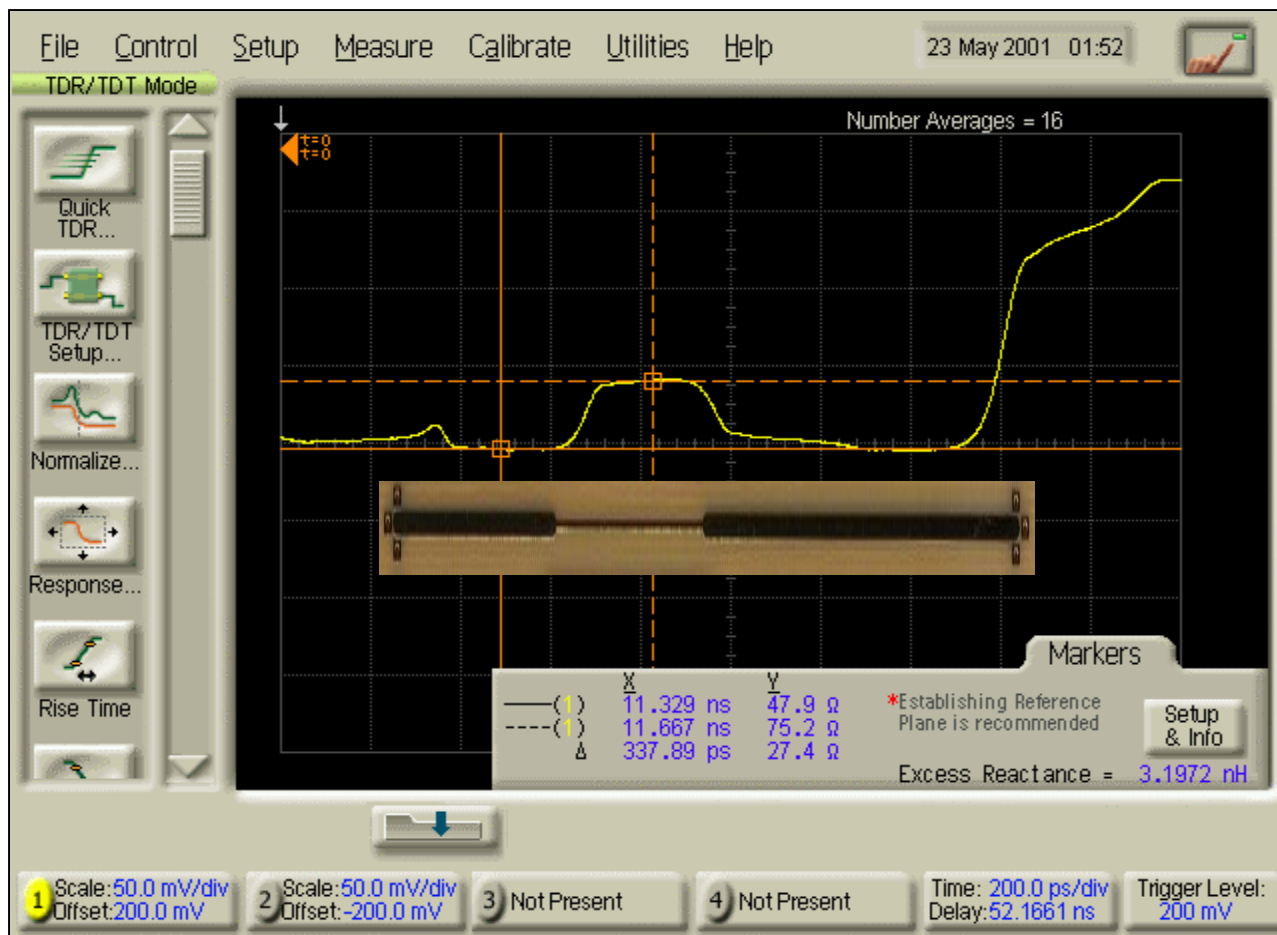


TDR is useful for characterizing passive, linear devices

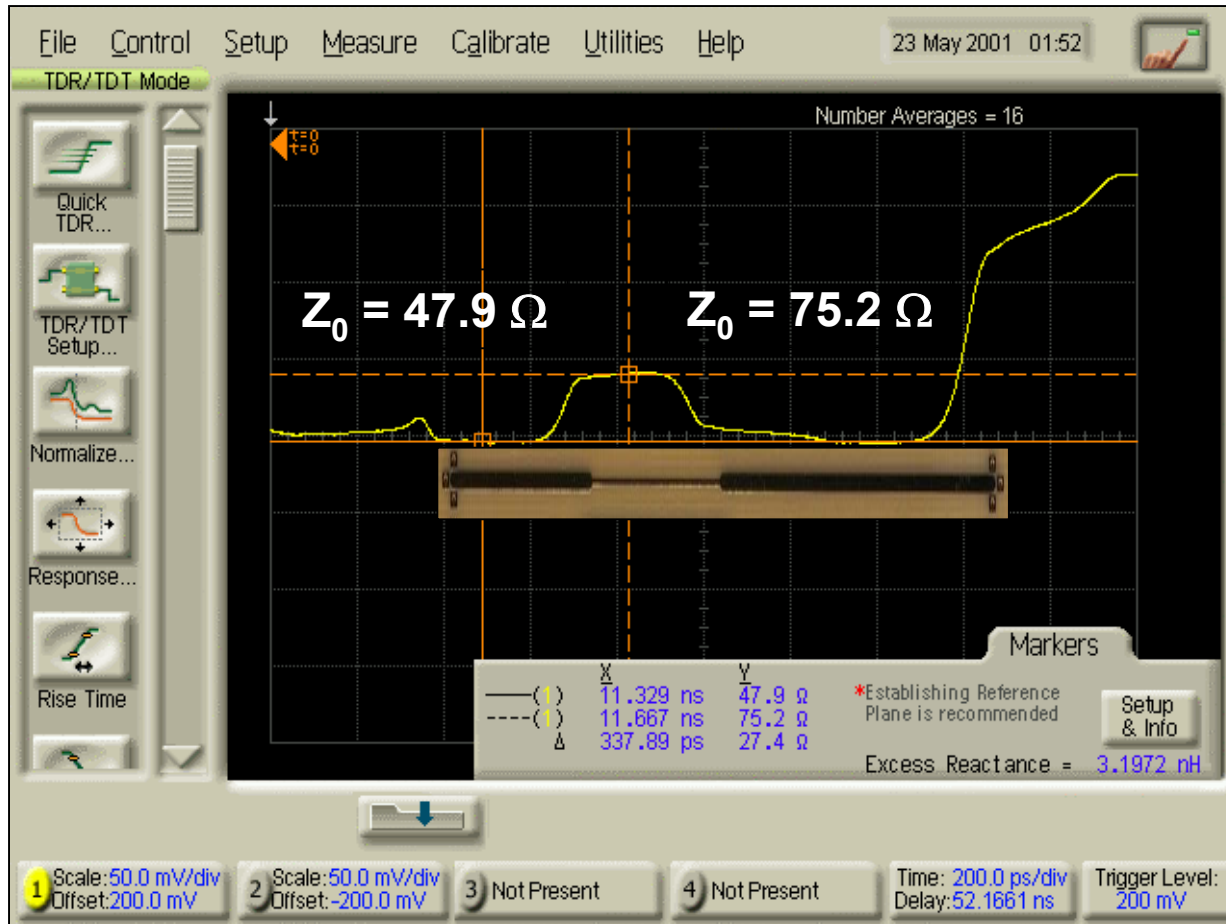


IC PACKAGES SOCKETS

Display in the Time Domain: TDR is “Instantaneous Impedance”



Quick Z_0 with TDR



Quick C, L Extraction with TDR



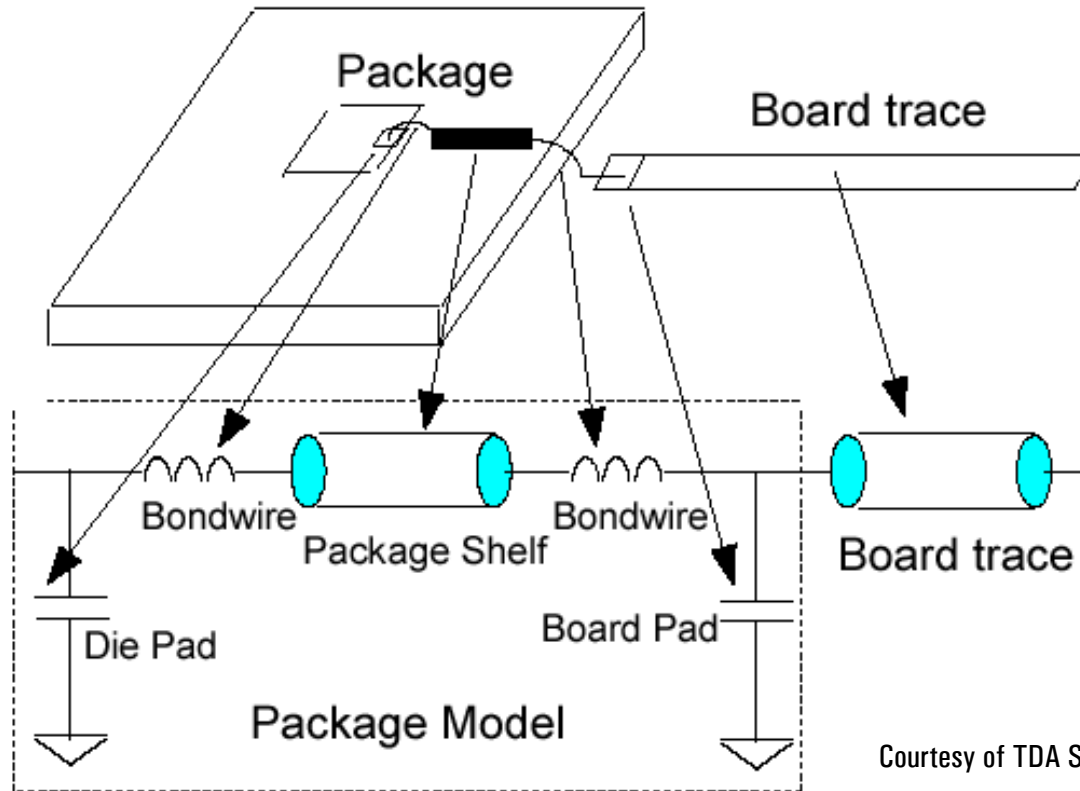
$$Z_0 = \sqrt{L/C}$$



Note: Excess Reactance = Excess Inductance or Excess Capacitance

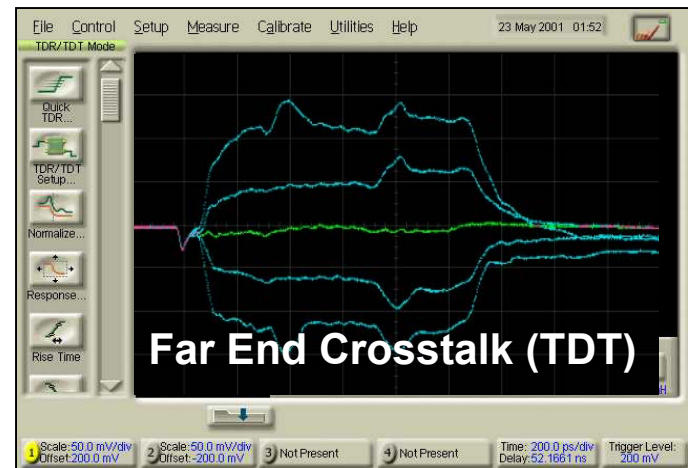
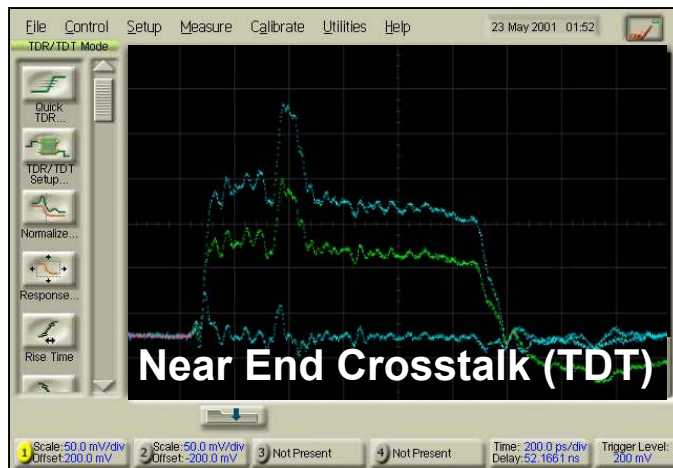
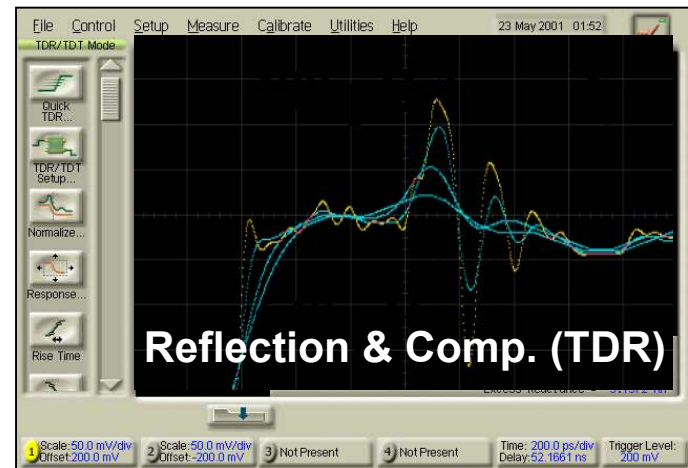
IConnect™ Modeling Software

TDR interconnect modeling



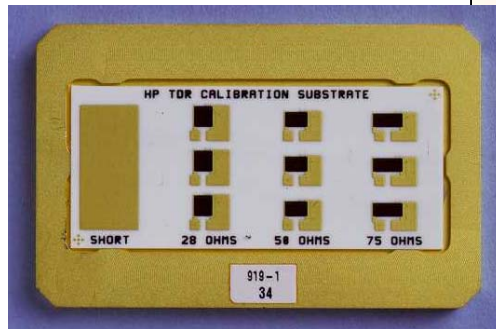
Physical model: correlates to the DUT geometry

Time Domain Analysis:TDR/TDT



How Do I Probe My Passive Device?

- Motherboards
- RIMMs
- Connectors
- Coaxial cables
- Microstrip



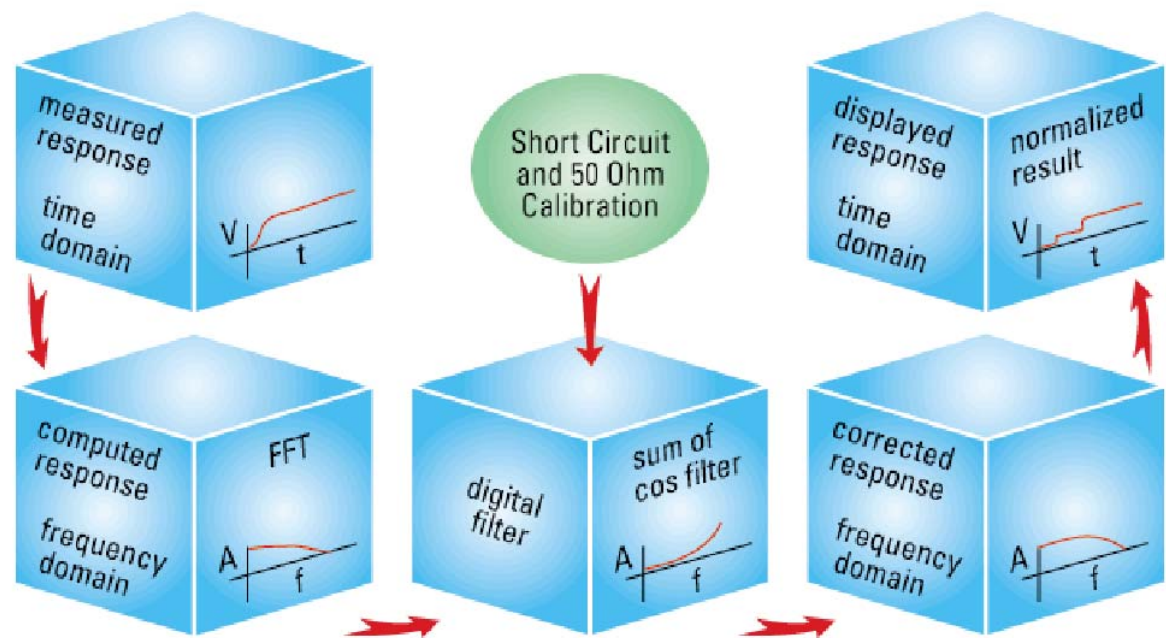
Calibration Substrate



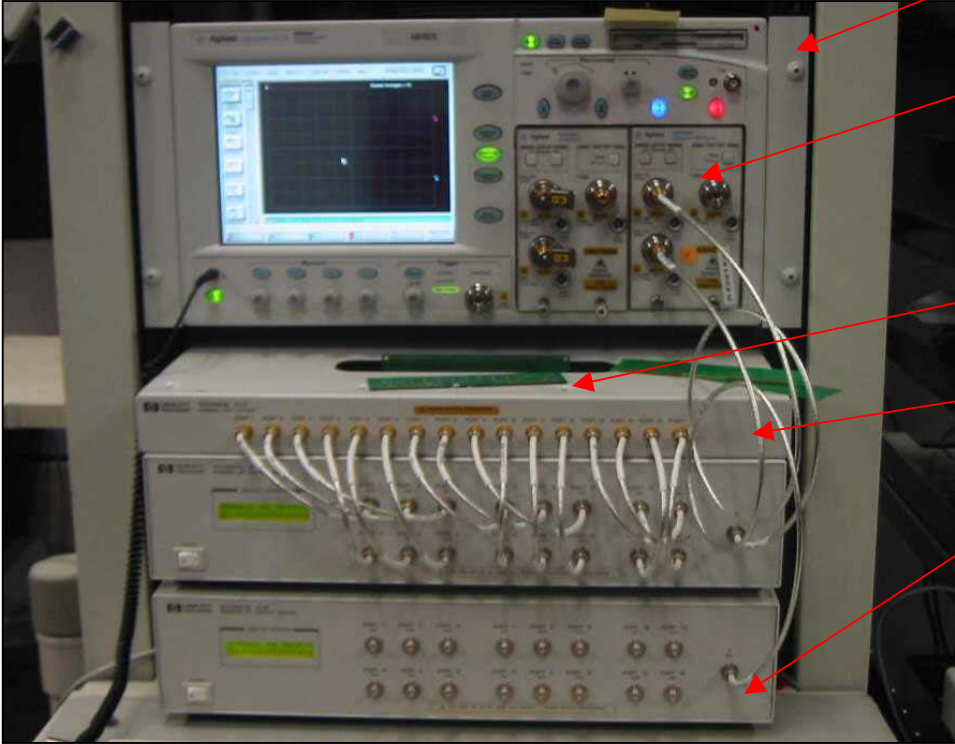
Single -ended probe
w/articulating arm (N1020A)

What is TDR Normalization?

- Digital Filter
- Constructed In Frequency Domain
- Removes Test Fixture Error
- Improves Impedance Accuracy



Differential TDR Test Set Up



86100A DCA

54754A Differential TDR Module

Device Under Test: Rambus™ RIMM

Test Fixture: Switch Matrix



Differential Impedance with and w/o TDR Normalization



Blue Trace - Normalized
Green Trace - Standard
Error = 2.3 ohms

Test Fixture

Device Under Test

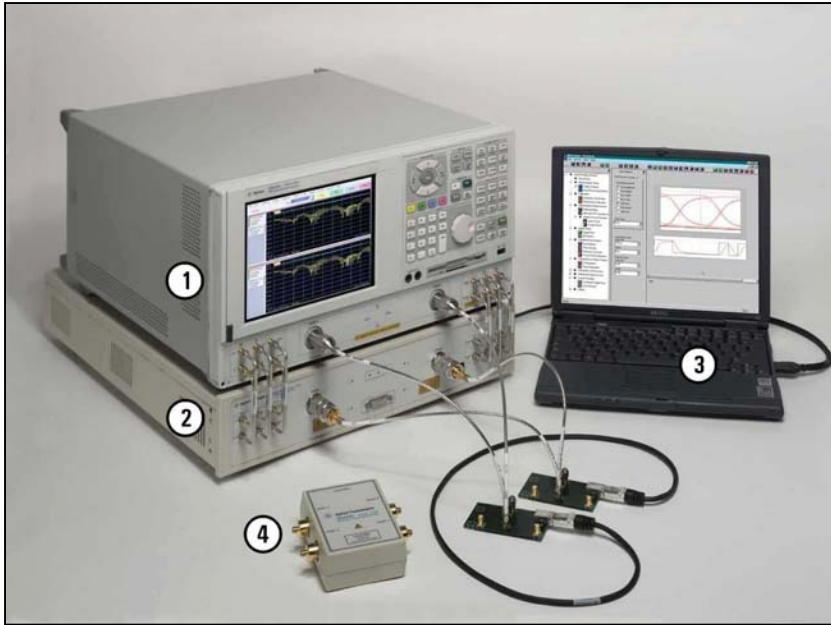
Summary

- **TDR is an easy to use, intuitive test tool**
- **Digital design speeds are increasing**
- **Normalization is critical**
- **Remove test fixture error**
- **TDR is an integral part of the signal integrity lab**

Agenda

- **Network Analyzer-Based System Configuration**
- **Differential Device Characterization**
- **Major Advantages of the VNA-Based System**

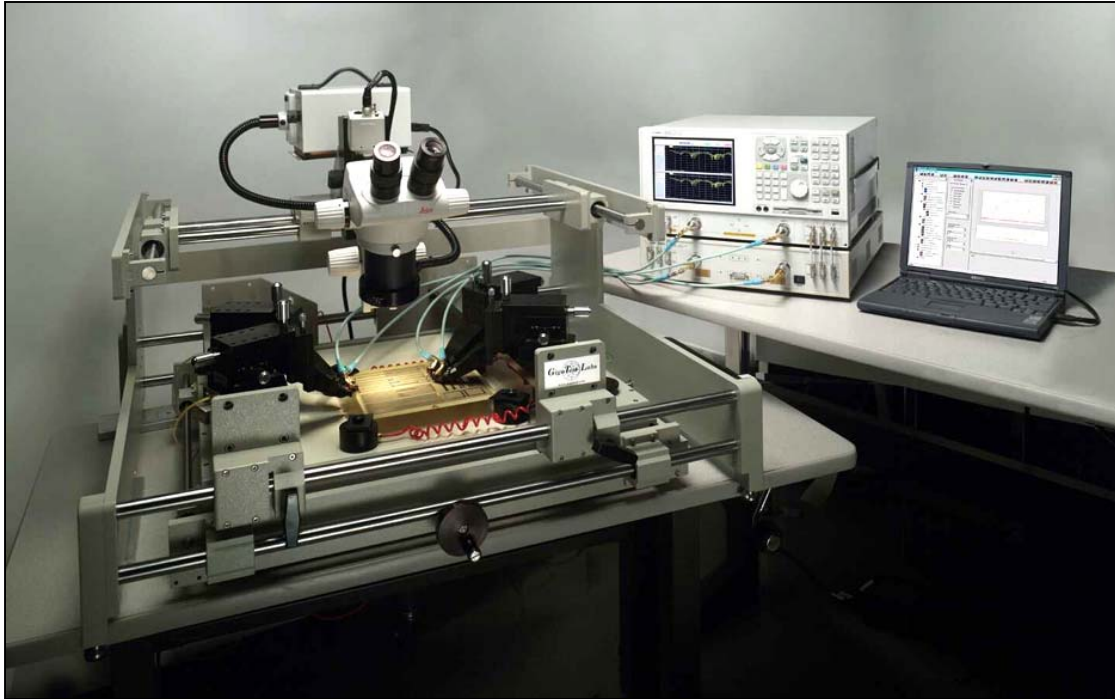
VNA-Based System Configuration



1. Network Analyzer
2. External Test Set
3. PC with Physical Layer Test System (PLTS) SW
4. Four-port Electronic Calibration Module or Mechanical Calibration Kit

| Currently Available Systems | | | | |
|-----------------------------|----------------------|---|---|---|
| RF BW (f_{max}) | Rise Time (10% -90%) | Approx. Effective Data Rate (inclusion to 1 st Harmonic) | Approx. Effective Data Rate (inclusion to 3 rd Harmonic) | Approx. Effective Data Rate (inclusion to 5 th Harmonic) |
| 6 GHz | 120 pS | 6 GB/sec | 3 GB/sec | 2 GB/sec |
| 9 GHz | 80 pS | 9 GB/sec | 4.5 GB/sec | 3 GB/sec |
| 20 GHz | 36 pS | 20 GB/sec | 10 GB/sec | 6.7 GB/sec |
| 50 GHz | 15 pS | 50 GB/sec | 25 GB/sec | 16.5 GB/sec |

System Configuration with GigaTest Probe Station



Probing solutions are recommended, particularly when:

- DUT cannot be connectorized due to physical constraints
- When fixturing (signal launchers, etc...) dominates measurement performance

Decision to use probing is performance dependent, not frequency dependent!

Frequency Domain Characterization

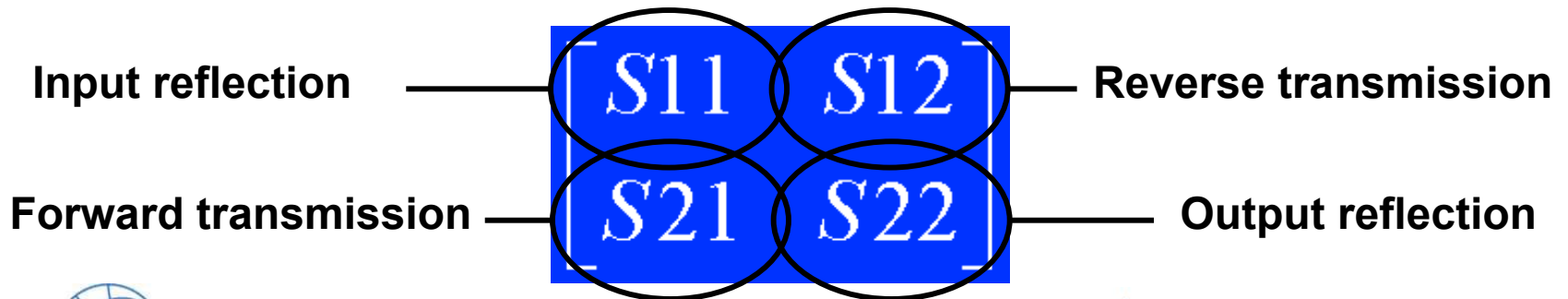
S-Parameters Answer the Question ...

If a single port of a device is **stimulated**,
what are the corresponding **responses**
on all ports of the device?



Frequency Domain Characterization

- An s-parameter is similar to a TDR or TDT response, but it only considers one frequency component at a time.
- Commonly represented in matrix form to fully characterize a device.
- A single-ended device with 2 ports has four s-parameters.



Unbalanced and Balanced Devices

- **Unbalanced (Single-ended) devices are referenced to gnd (S-parameters)**



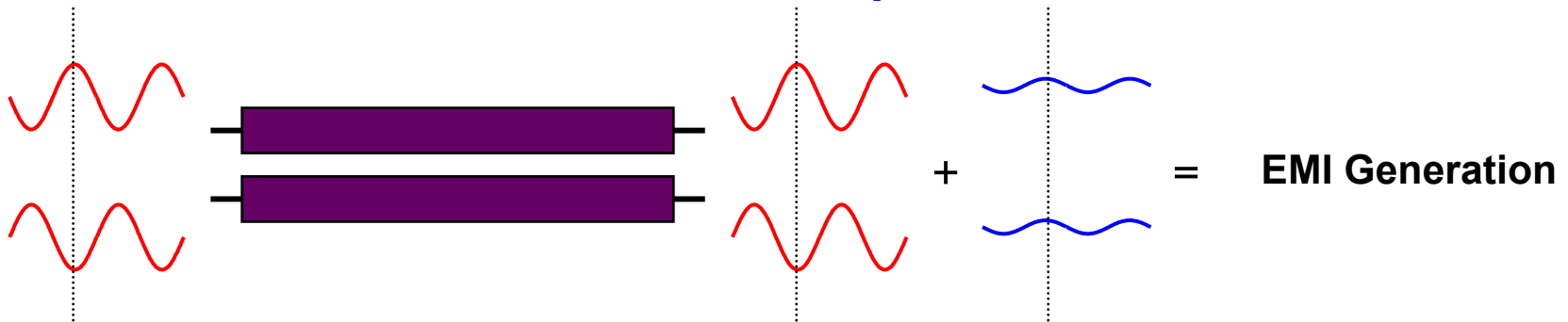
- **Balanced (Differential) devices are pairs (Mixed-Mode S-parameters)**



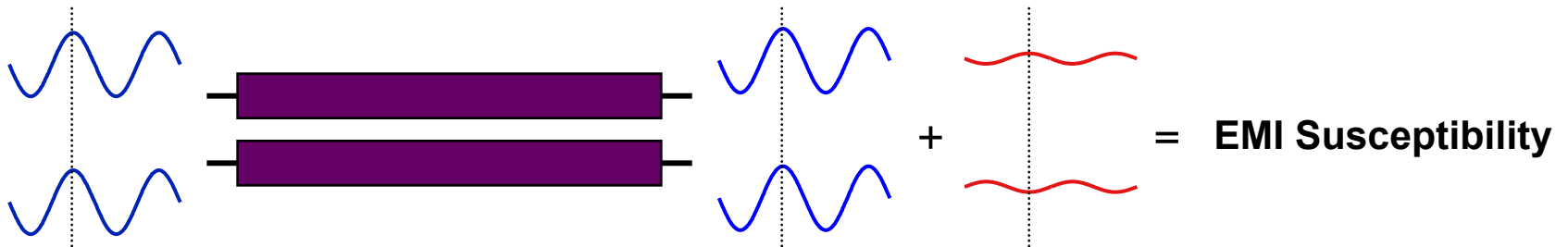
What About Non-Ideal Devices?

Mode conversions occur...

- **Differential-stimulus** to **common-response** conversion



- **Common-stimulus** to **differential-response** conversion



Balanced Device Characterization

Differential Stimulus/Response

- Intended Operating Mode
- Forward and Reverse Transmission and Reflection

Mode Conversion from C-to-D

- Typically Overlooked
- Results from Device Asymmetry
- Related to Susceptibility to EMI

| | | | |
|------------|------------|------------|------------|
| S_{DD11} | S_{DD12} | S_{DC11} | S_{DC12} |
| S_{DD21} | S_{DD22} | S_{DC21} | S_{DC22} |
| S_{CD11} | S_{CD12} | S_{CC11} | S_{CC12} |
| S_{CD21} | S_{CD22} | S_{CC21} | S_{CC22} |

Mode Conversion from D-to-C

- Typically Overlooked
- Results from Device Asymmetry
- Related to Generation of EMI

Common Stimulus/Response

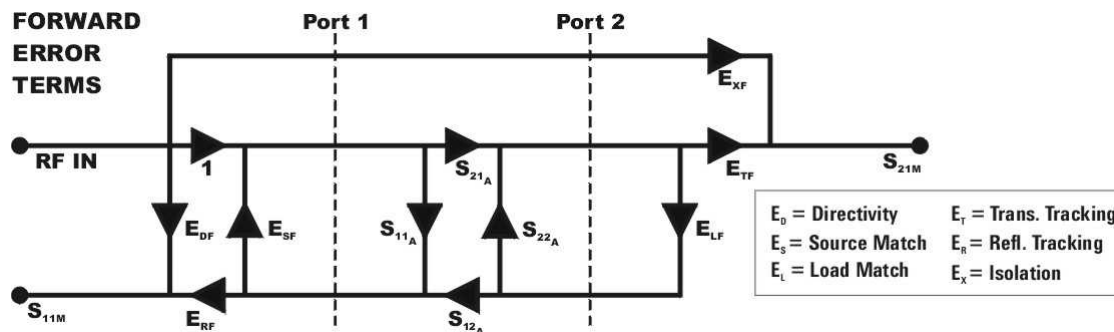
- Mode of Noise
- Forward and Reverse Transmission and Reflection

Advantages of the VNA-Based System

- Superior **accuracy**
- Significantly better **dynamic range**
 - Up to approx. -110 dB
- Greater ability to **remove unwanted effects** of fixtures from the measurement with greater accuracy
 - Gating, Port Extensions, De-Embedding, Direct Measurement
- **Comprehensive characterization and analysis**

Superior Accuracy

- Inherent Source and Receiver Accuracy
 - Low Noise Source, Less Random Error
 - Tuned, Super-Heterodyne, Phase-Locked Receiver
- Precision, Phase-Stable Test Cables and Connectors. Metrology Grade Calibration Kits
- Systematic Error-Correction with Four-Port Error Model
 - Well-Defined Calibration and DUT Reference Planes



Superior Accuracy

- **TDR uses integrated waveform**
 - **Receiver must discriminate small signal of interest from broadband content**
 - **Best results require TDR and DUT edge rates to match**
- **VNA uses standing waves**
 - **Results are accurate for any edge rate**
 - **Receiver is tuned to the source, like a tracking filter**

Why is Dynamic Range Important?

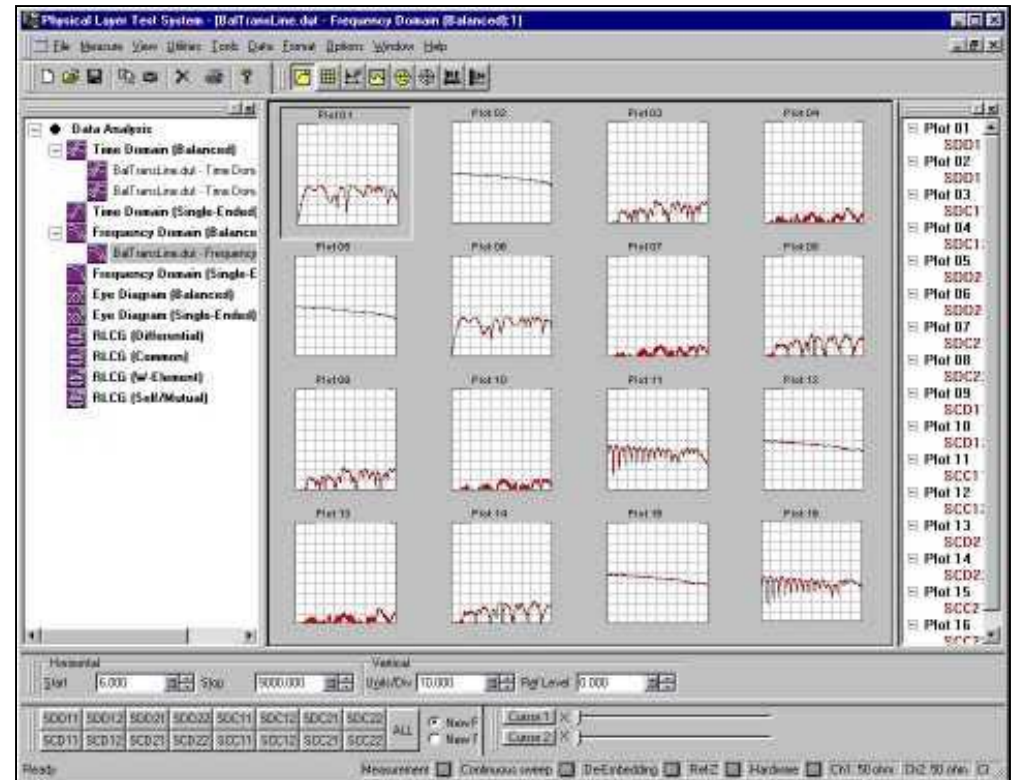
- **Crosstalk**
- **Mixed-Signal applications**
- **Helps defeat masking effects**
 - **Greater ability to resolve deep/hidden structures**
- **Important for Mode Conversion, yet often overlooked**
 - **Related to susceptibility and generation of EMI**

Removing Unwanted Effects from the Measurement

- **Time-Domain Gating**
 - Easiest method. Less accurate.
- **Port Extension**
 - Also easy. Requires “ideal” fixturing.
- **De-embedding**
 - More difficult. Extremely accurate!
- **Calibration at the DUT Reference Plane**
 - Requires probing solutions or calibration standards on board.

Comprehensive Characterization and Analysis

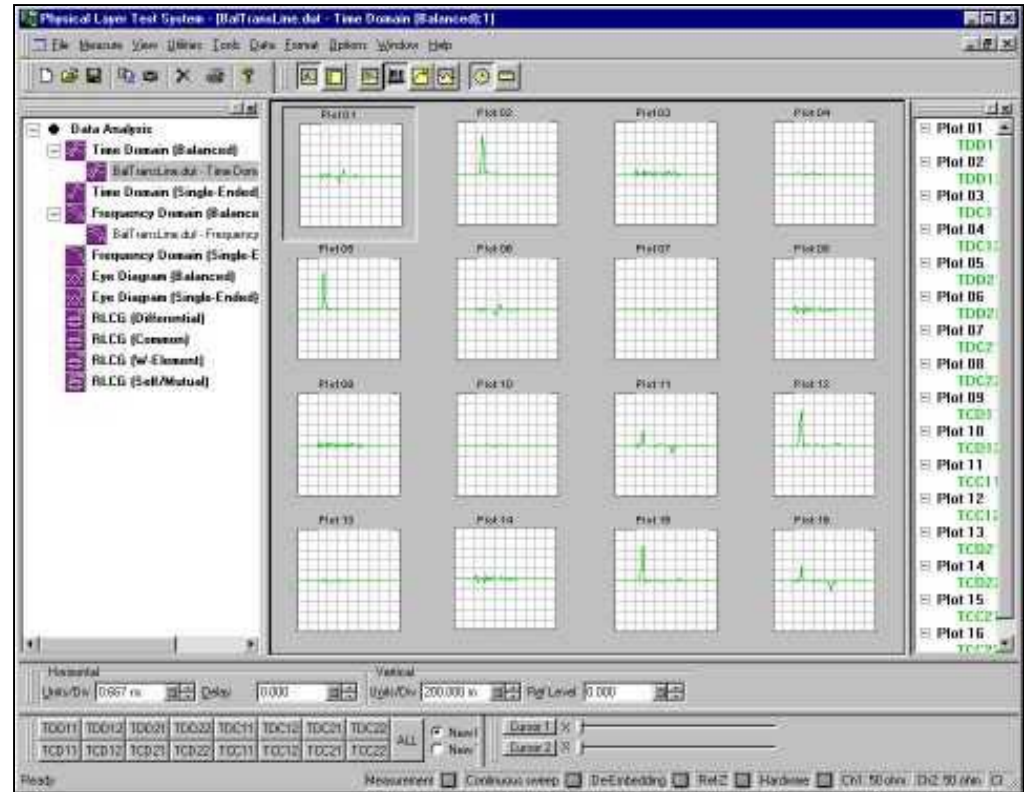
- Frequency Domain
 - Forward and reverse transmission and reflection
 - Single-ended-, differential-, and mixed-modes
 - 32 frequency domain plots per measurement
 - Log mag, linear mag, phase, group delay, Smith, Polar, real, imaginary



Comprehensive Characterization and Analysis

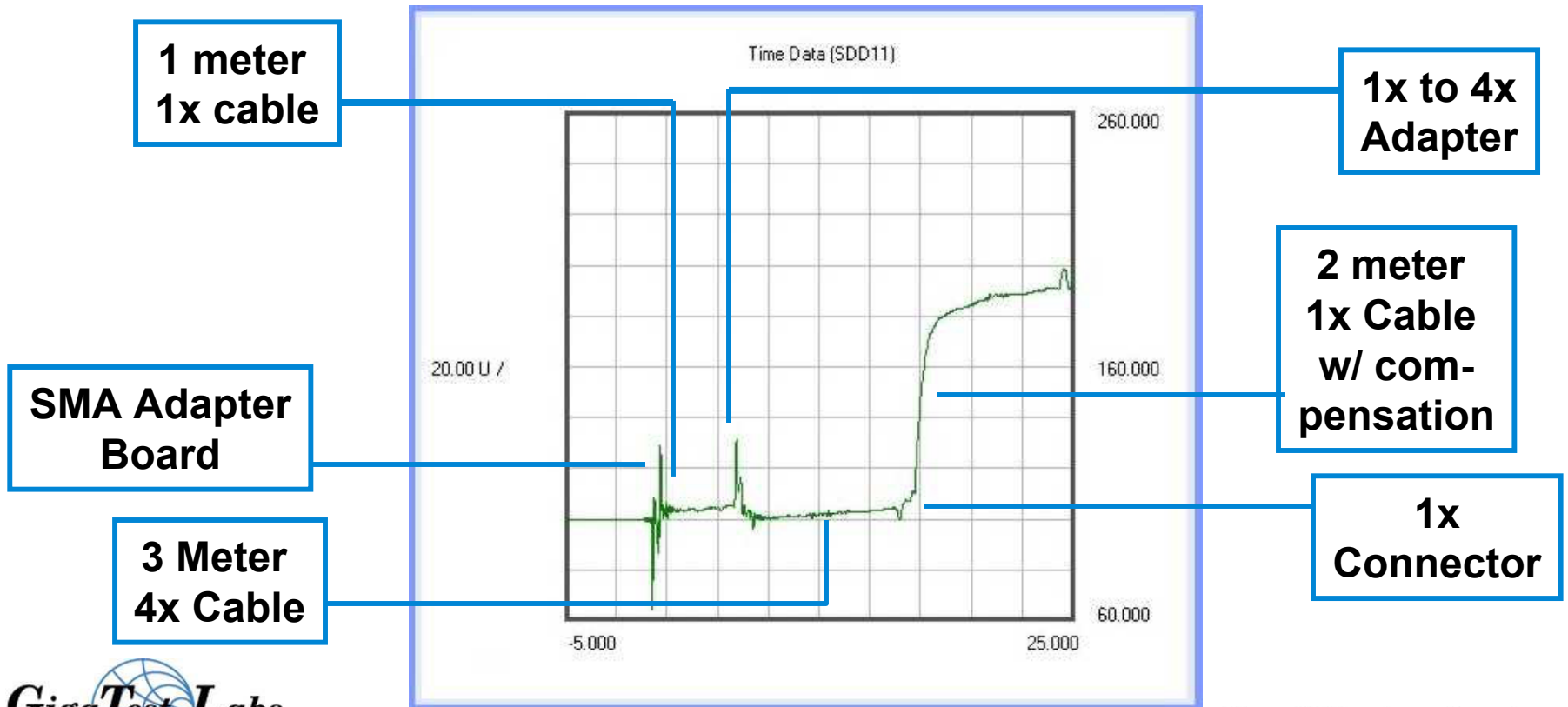
- Time Domain

- Input and output TDR and TDT
- Single-ended-, differential-, and mixed-modes
- 32 time domain plots per measurement
- Impulse or step
- Volts, real, log mag, or impedance
- nS or cm



Comprehensive Characterization and Analysis

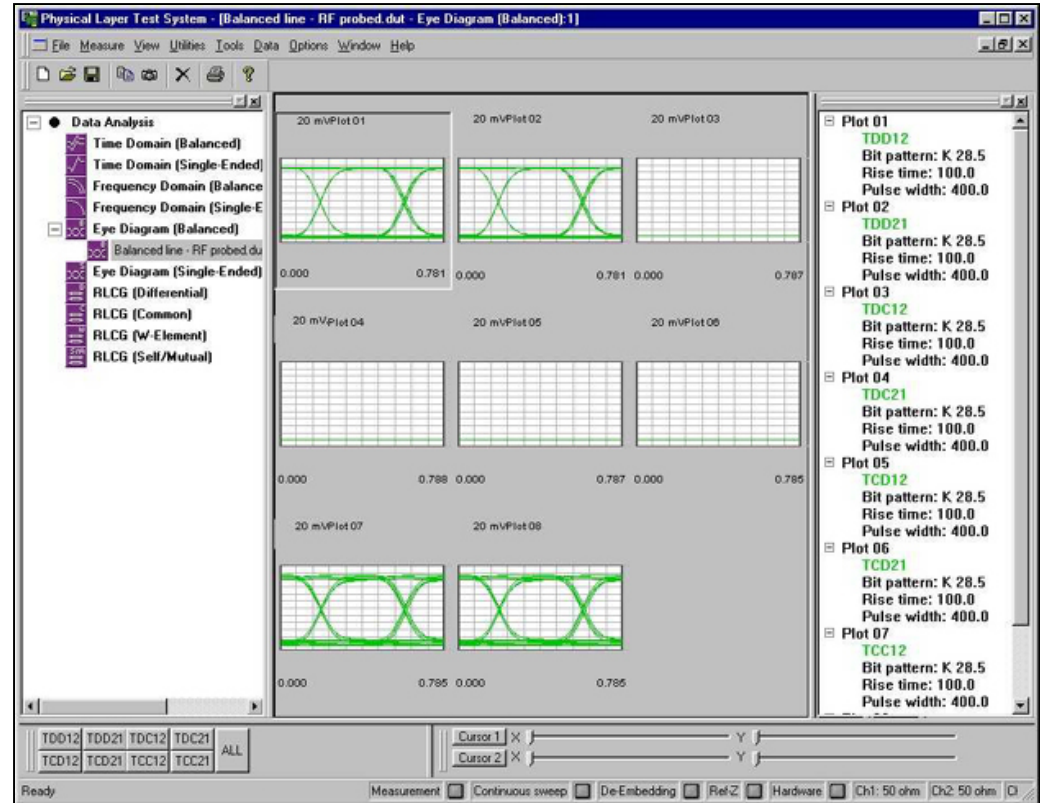
Differential Impedance Profile of Complex Structure



Comprehensive Characterization and Analysis

- **Measurement-based Eye Diagrams**

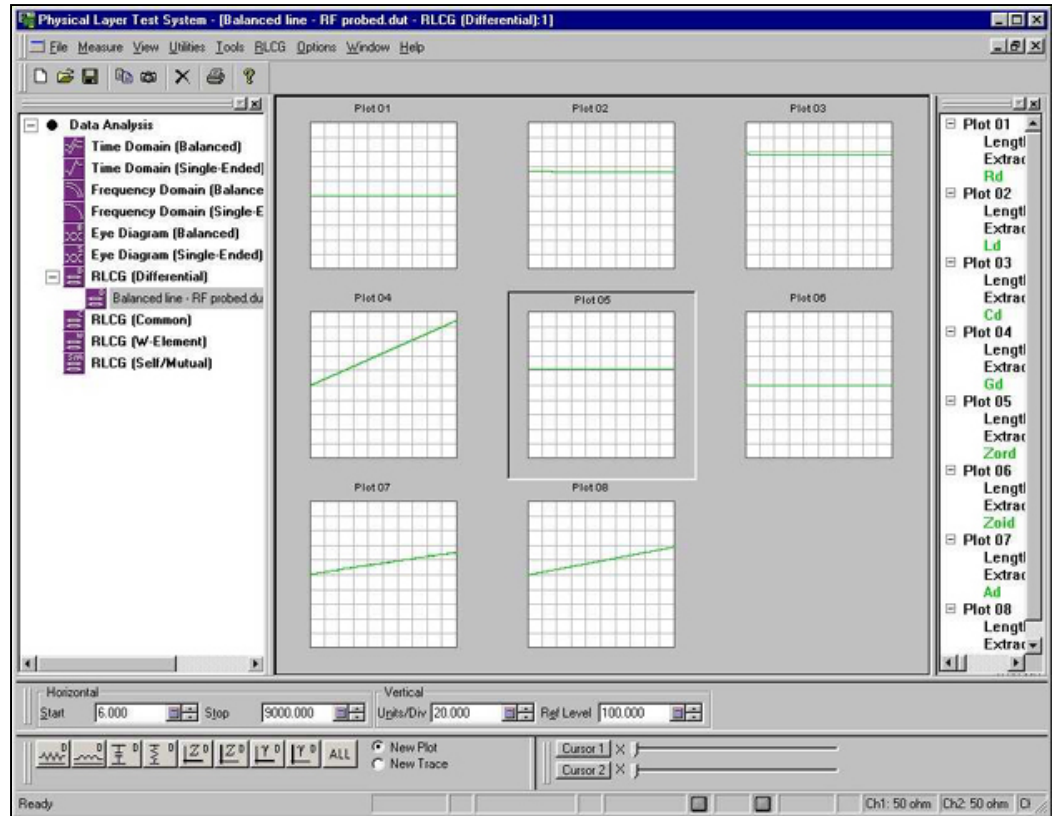
- **Forward and Reverse Transmission and Reflection**
- **Single-ended-, Differential-, Common-, and Mixed-Modes**
- **Virtual Pulse Generator**
 - **Arbitrary Bit Patterns**



Comprehensive Characterization and Analysis

- RLCG Model Extraction

- Differential, Common, W-Element, Self and Mutual Terms
- Linkage to modeling and simulation tools
 - ADS
 - Hspice



Ideal Instrument

The VNA-Based System Takes the Best from Each World:

● From RF World ...

- Frequency Domain Data
- Accuracy
- Dynamic Range
- Well-Defined Reference Plane
- Removal of Fixture Effects
- Complete Characterization

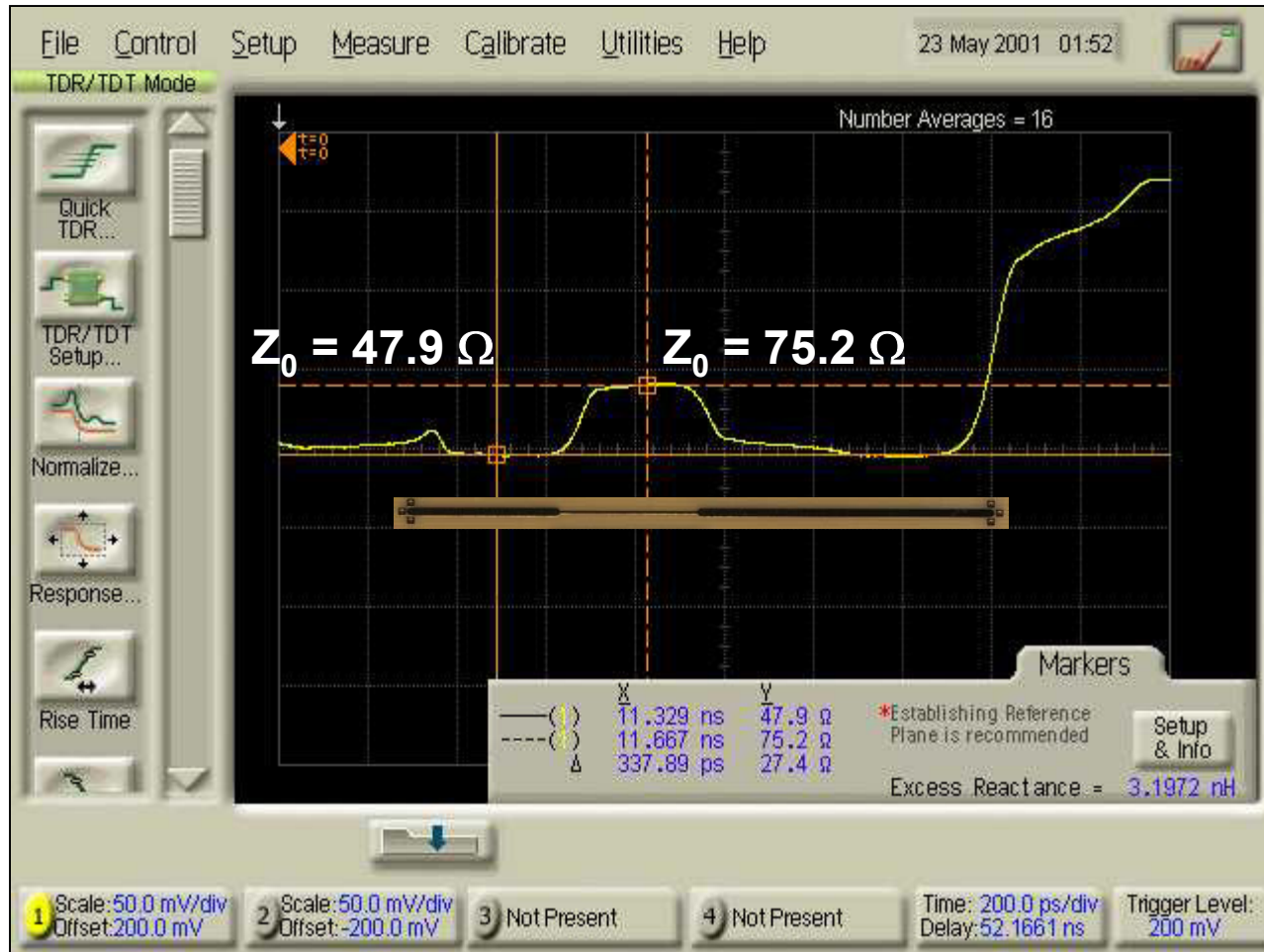
● From Digital World ...

- TDR & TDT Responses
- Impedance Profiling
- Eye Diagrams
- RLCG Model Extraction

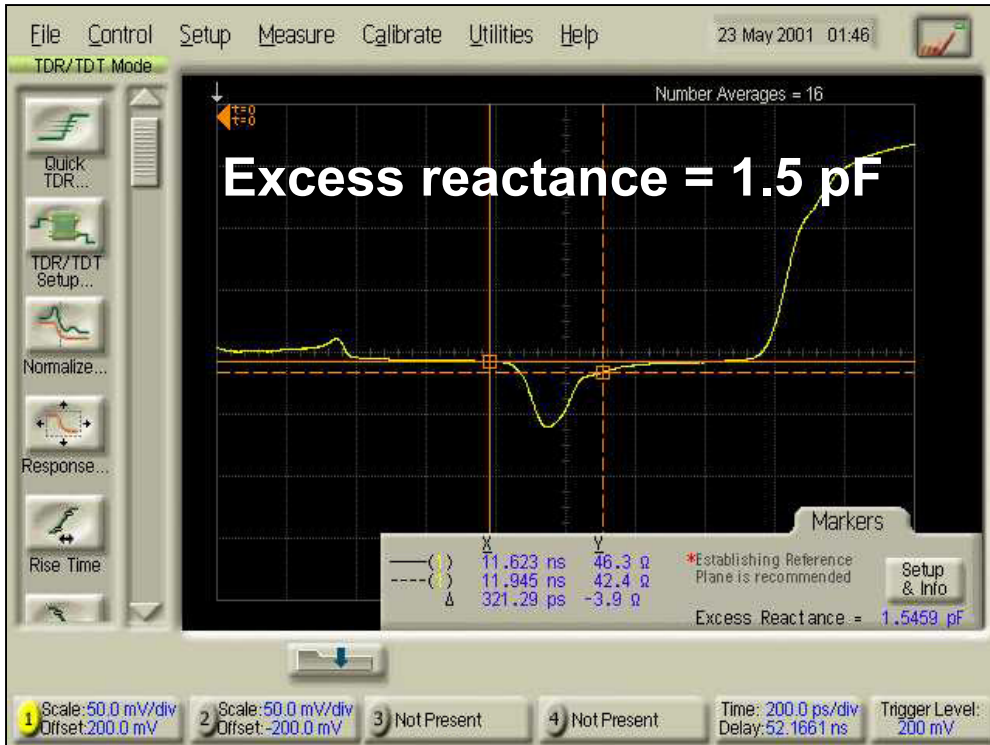
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- **SNR is better for VNA than TDR**
 - **important for low insertion loss components**
 - **Important for low levels of mode conversion**
- **The PLTS simplifies the analysis of 4 port differential interconnects**

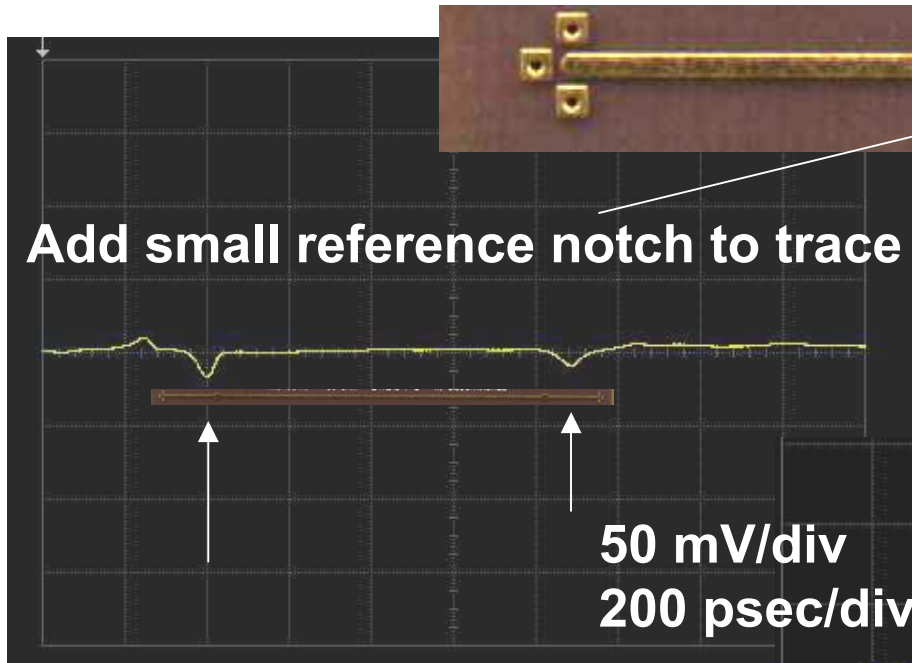
Quick Z_0 with TDR



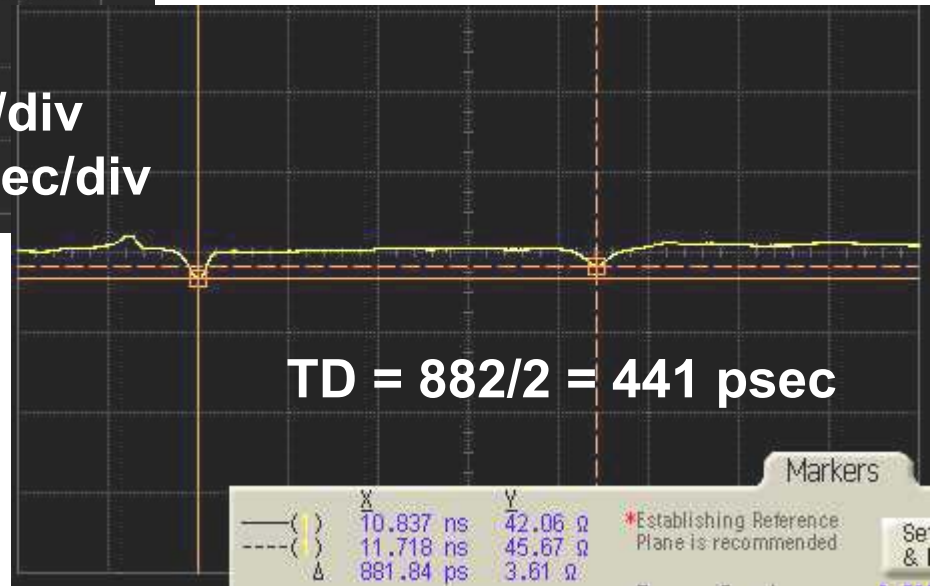
Quick C, L Extraction with TDR



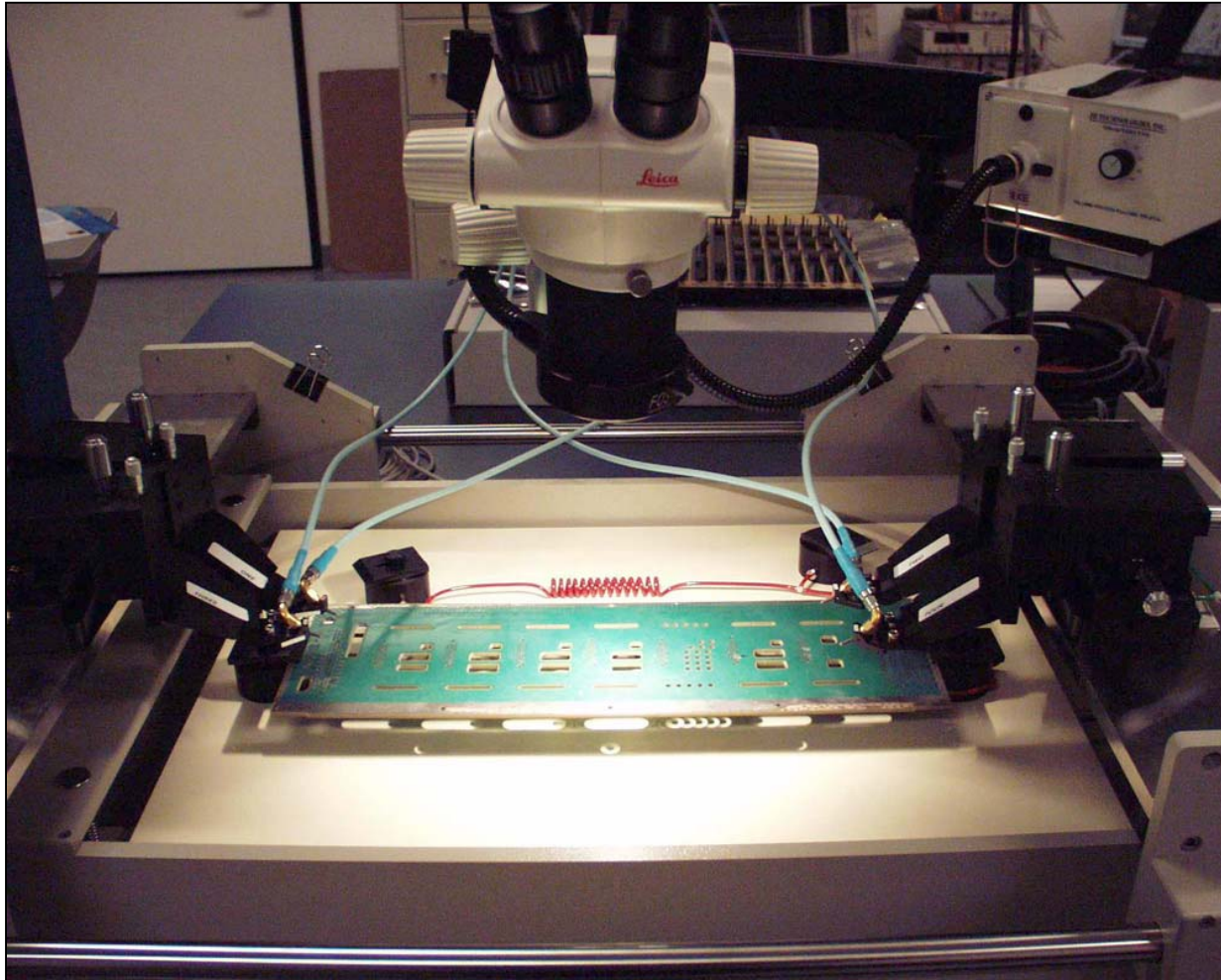
Quick, Accurate Propagation Speed From TDR



Len = 3 inches
Vel = 3 inches / 0.44 nsec
= 6.82 inches/nsec



Fast, Complete Differential Pair Characterization with 4 port VNA Based System



Data Management: 16 Element S Parameter Matrix

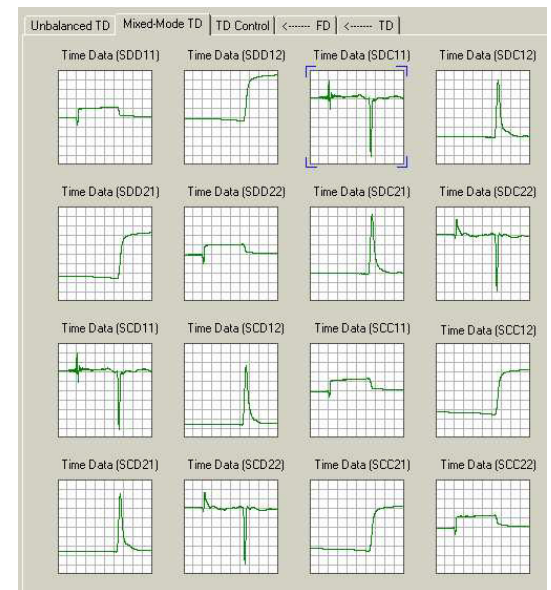
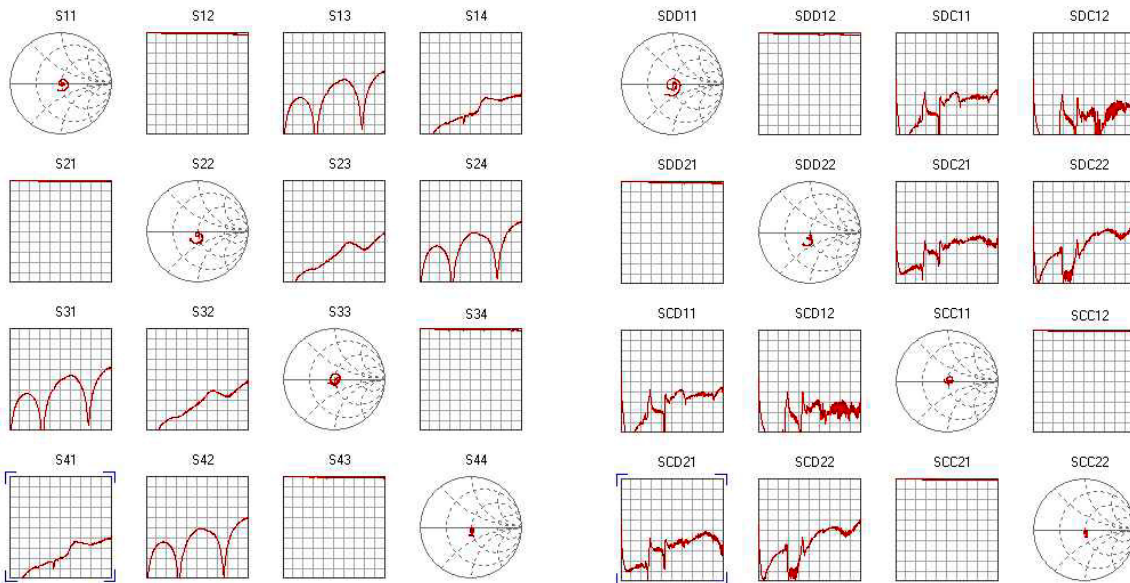
Single ended
S Parameters



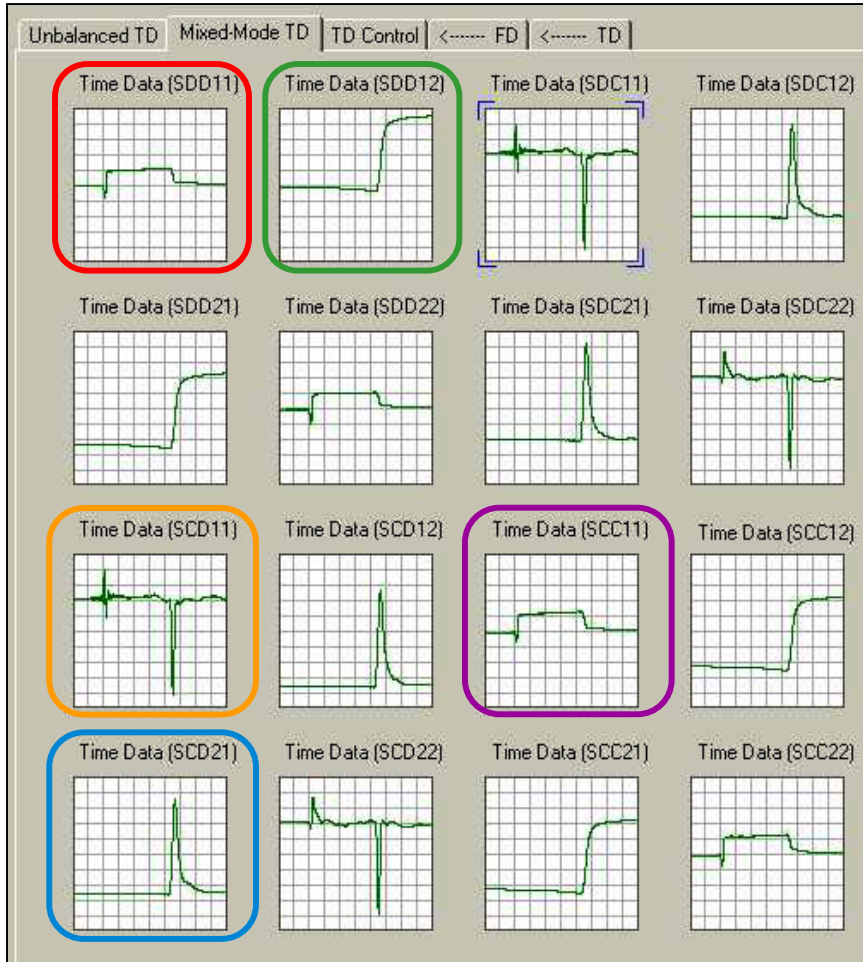
Mixed Mode
S Parameters



Mixed Mode
S Parameters
Displayed in the
Time Domain



Balanced Time Domain Response



Five important terms:

SDD11: Differential Impedance

SCC11: Common impedance

SDD21: transmitted diff signal

SCD21: mode conversion: diff signal in, common signal out

SCD11: mode conversion: diff signal in, common signal reflected back

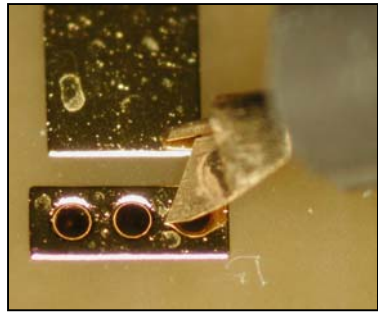
Which System is Right for You?

- **TDR based system is for you if you....**
 - **Don't want to know about S parameters**
 - **Want to quickly generate first order models of transmission lines and small discontinuities**
 - **Want to be able to build general models of passive structures**

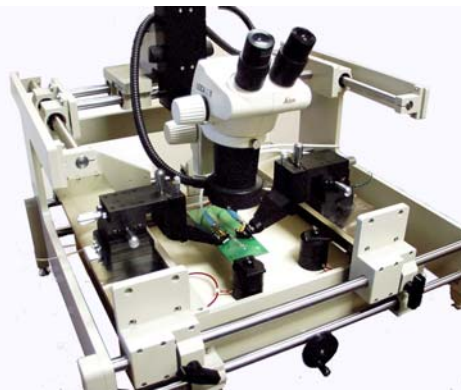
- **VNA based system is for you if you...**
 - **Have low loss or low insertion loss components**
 - **Want to fully characterize differential pairs quickly**

- **Use both systems if you....**
 - **Want the most versatility for quick and easy first order characterization of interconnects**
 - **Want full, complete characterization of diff pairs and small coupling effects at high bandwidth**

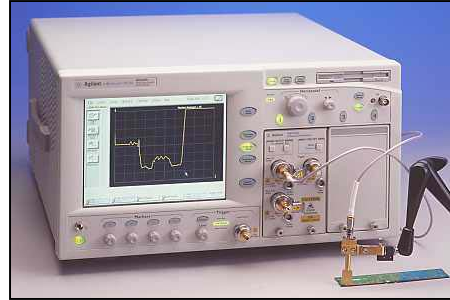
GigaTest Labs Signal Integrity Engineering Turn Key Systems



DUT +
microprobes

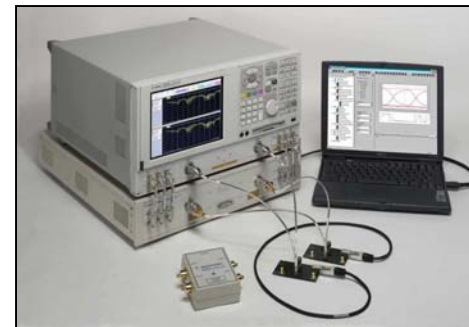
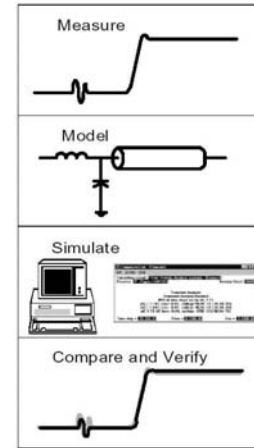


GigaTest Probe
Station



TDR

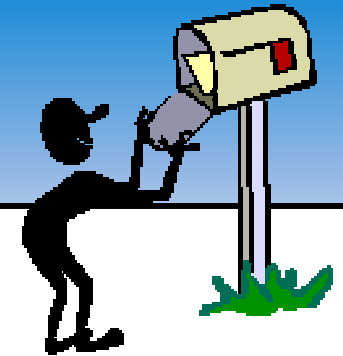
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Physical Layer Test System
(PLTS): VNA + software

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